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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Paul Hoisington et al.
Serial No. : 10/782,367
Filed : February 19, 2004
Title : PRINthead

Art Unit :
Examiner :

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

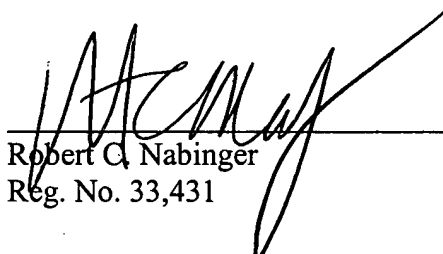
Applicants submit the references listed on the attached form PTO-1449.

This statement is being filed before the receipt of a first Office action on the merits.

Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: May 19, 2004


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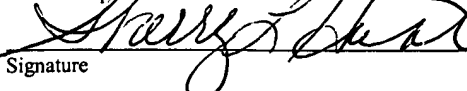
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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09991-121001	Application No. 10/782,367
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Paul Hoisington et al.	
Filing Date February 19, 2004		Group Art Unit	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	US 2004/0004649 A1	01/08/04	Bibl et al.			
	AB	5,742,313	04/21/98	Hine			
	AC	5,701,148	12/23/97	Moynihan et al.			
	AD	4,995,940	02/26/91	Hine et al.			
	AE	4,961,082	10/02/90	Hoisington et al.			
	AF	4,940,995	07/10/90	Hine et al.			
	AG	4,788,556	11/29/88	Hoisington et al.			
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	Kim et al., "Nanostructured Surfaces for Dramatic Reduction of Flow Resistance in Droplet-Based Microfluidics", IEEE Conf. MEMS, Las Vegas, NV, pp. 479-482, Jan. 2002
	AR	Keiran Lindsey, "DMD00 The 2000 Guide to the Membrane Industry", December 2000
	AS	Robert T. DeHoff, "Capillarity Effects in Thermodynamics", Thermodynamics in Materials Science, pp. 355-401, 1993
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	